

Si9424DY

Single P-Channel 2.5V Specified PowerTrench MOSFET

General Description

This P-Channel 2.5V specified MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize on-state resistance and yet maintain superior switching performance.

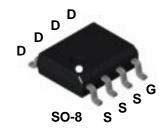
These devices are well suited for low voltage and battery powered applications where low in-line power loss and fast switching are required.

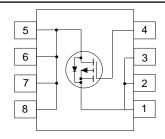
Applications

- DC/DC converter
- Load switch
- Battery Protection

Features

- -8.0 A, -20 V. $R_{DS(on)} = 0.024~\Omega~$ @ $V_{GS} =$ -4.5 V $R_{DS(on)} = 0.032~\Omega~$ @ $V_{GS} =$ -2.5 V.
- Low gate charge (23nC typical).
- Fast switching speed.
- $\bullet \;\;$ High performance trench technology for extremely low $R_{\mbox{\tiny DS(ION)}}.$
- High power and current handling capability.





Absolute Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		-20	V
V _{GSS}	Gate-Source Voltage		± 10	V
I _D	Drain Current - Continuous	(Note 1a)	-8.0	Α
	- Pulsed		-50	
P _D	Power Dissipation for Single Operation	(Note 1a)	2.5	W
		(Note 1b)	1.2	
		(Note 1c)	1	
TJ, Tsta	Operating and Storage Junction Temperature Range		-55 to +150	°C

Thermal Characteristics

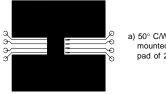
$R_{\theta^{JA}}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	50	∘C/W
R _{AJC}	Thermal Resistance, Junction-to-Case	(Note 1)	25	°C/W

Package Outlines and Ordering Information

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Device Marking	Device Reel Size		Tape Width	Quantity		
9424	Si9424DY	13"	12mm	2500 units		

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$	-20			V
ABVDSS	Breakdown Voltage Temperature Coefficient	I_D = -250 μ A, Referenced to 25°C		-24		mV/∘C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -16 \text{ V}, V_{GS} = 0 \text{ V}$			-1	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	$V_{GS} = 10 \text{ V}, V_{DS} = 0 \text{ V}$			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -10 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
On Char	acteristics (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	-0.4	-0.8	-1.5	V
AVGS(th)	Gate Threshold Voltage Temperature Coefficient	I_D = -250 μ A, Referenced to 25°C		5		mV/°C
R _{DS(on)}	Static Drain-Source On-Resistance	$V_{GS} = -4.5 \text{ V}, I_D = -8 \text{ A}$ $V_{GS} = -4.5 \text{ V}, I_D = -8 \text{ A}, T_J = 125 ^{\circ}\text{C}$ $V_{GS} = -2.5 \text{ V}, I_D = -7 \text{ A}$		0.019 0.026 0.027	0.024 0.039 0.032	Ω
I _{D(on)}	On-State Drain Current	$V_{GS} = -4.5 \text{ V}, V_{DS} = -5.0 \text{ V}$	-50			Α
G FS	Forward Transconductance	$V_{DS} = -5 \text{ V}, I_{D} = -8 \text{ A}$		28		S
Dvnamio	: Characteristics					
C _{iss}	Input Capacitance	V _{DS} = -10 V, V _{GS} = 0 V,		2260		pF
Coss	Output Capacitance	f = 1.0 MHz		500		рF
C _{rss}	Reverse Transfer Capacitance			205		pF
Switchin	g Characteristics (Note 2)					
t _{d(on)}	Turn-On Delay Time	$V_{DD} = -10 \text{ V}, I_D = -1 \text{ A},$		8	16	ns
t _r	Turn-On Rise Time	$V_{GS} = -4.5 \text{ V}, R_{GEN} = 6 \Omega$		15	27	ns
t _{d(off)}	Turn-Off Delay Time			98	135	ns
t _f	Turn-Off Fall Time			35	55	ns
$\overline{Q_g}$	Total Gate Charge	$V_{DS} = -10 \text{ V}, I_{D} = -8 \text{ A},$		23	33	nC
$\overline{Q_gs}$	Gate-Source Charge	$V_{GS} = -5 V$,		5.5		nC
Q_{gd}	Gate-Drain Charge			4		nC
Drain-Sc	ource Diode Characteristics an	d Maximum Ratings				
l _s	Maximum Continuous Drain-Source Diode Forward Current				-2.1	Α
$\overline{V_{SD}}$	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = -2.1 A (Note 2)		-0.75	-1.2	V

1: $R_{\theta JA}$ is the sum of the junction-to-case and case-to-ambient resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design while $R_{\theta JA}$ is determined by the user's board design.



a) 50° C/W when mounted on a 0.5 in² pad of 2 oz. copper.

b) 105° C/W when mounted on a 0.02 in² pad of 2 oz. copper.

c) 125° C/W when mounted on a 0.003 in² pad of 2 oz. copper.





Scale 1 : 1 on letter size paper

2: Pulse Test: Pulse Width $\leq 300~\mu s$, Duty Cycle $\leq 2.0\%$

Typical Characteristics

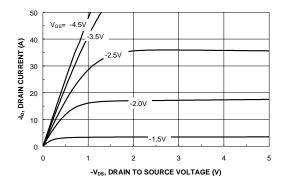
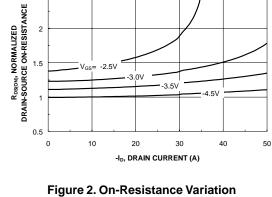


Figure 1. On-Region Characteristics.



2.5

Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

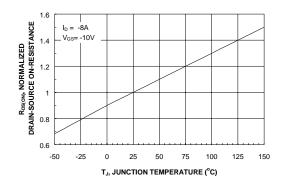


Figure 3. On-Resistance Variation with Temperature.

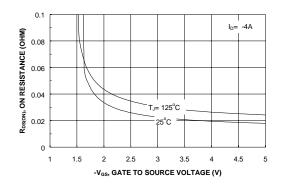


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

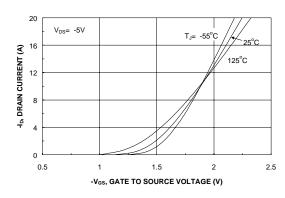


Figure 5. Transfer Characteristics.

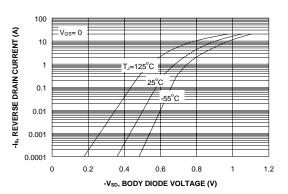
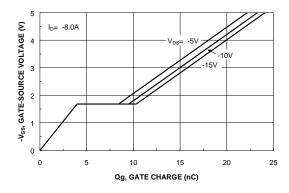


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics (continued)



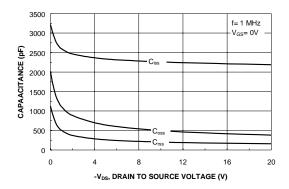
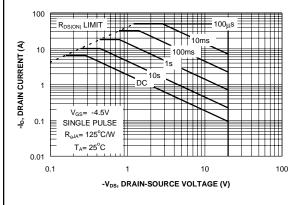


Figure 7. Gate Charge Characteristics.





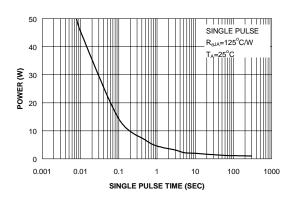


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

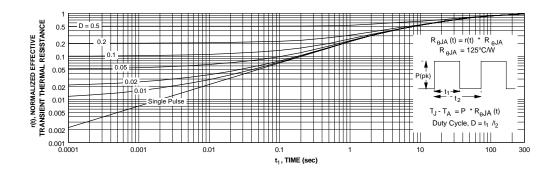


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient themal response will change depending on the circuit board design.

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